

• General Description

This silicon carbide Power MOSFET device has been developed using ZMJ's advanced 1st generation SiC MOSFET technology. The device features a very low $R_{DS(on)}$ over the entire temperature range combined with low capacitances and very high switching operations. It improves application performance in frequency, energy efficiency, system size and weight reduction.

• Features

- High Blocking Voltage
- High Speed Switching With Low Capacitances
- Low $R_{DS(on)}$ to Minimize Conductive Loss
- Low Gate Charge For Fast Switching
- Low Thermal Resistance
- AEC-Q101 Qualified

• Application

- Motor Drives
- On Board Charger
- DC-DC
- Auxiliary Drives

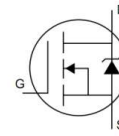
• Ordering Information:

Part NO.	ZMCA100KR170C3
Marking	ZMC100KR170
Packing Information	TUBE
Basic ordering unit (pcs)	450

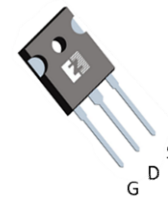
• Absolute Maximum Ratings ($T_A=25^{\circ}\text{C}$, unless otherwise specified)

Parameter	Symbol	Conditions	Min.	Max.	Unit
Drain-Source Voltage	V_{DS}		-	1700	V
Gate-Source Voltage①	V_{GS}	Transient Voltage	-10	25	V
	V_{GS}	Static Voltage	-10	24	V
Recommended turn on gate voltage	$V_{GS(on)}$		15	18	V
Recommended turn off gate voltage	$V_{GS(off)}$		-4	0	V
Continuous Drain Current	I_D	$V_{GS}=18\text{V}, T_C=25^{\circ}\text{C}$	-	5.3	A
	I_D	$V_{GS}=18\text{V}, T_C=75^{\circ}\text{C}$	-	4.4	A
	I_D	$V_{GS}=18\text{V}, T_C=100^{\circ}\text{C}$	-	3.8	A
Pulsed Drain Current ①	I_{DM}	Pulsed; $t_p \leq 10 \mu\text{s}$; $T_C = 25^{\circ}\text{C}$;	-	21.2	A
Total Power Dissipation	P_D	$T_C=25^{\circ}\text{C}$	-	45	W
Total Power Dissipation	P_D	$T_A=25^{\circ}\text{C}$	-	3.8	W
Operating Junction Temperature	T_J		-55	175	$^{\circ}\text{C}$
Storage Temperature	T_{STG}		-55	175	$^{\circ}\text{C}$
ESD Level (HBM)	CLASS 1C				

• Product Summary



$V_{DS} = 1700\text{V}$
 $R_{DS(on)} = 750\text{m}\Omega$
 $I_D = 5.3\text{A}$



TO-247-3



•Thermal resistance

Parameter	Symbol	Min.	Typ.	Max.	Unit
Thermal resistance, junction - case	R_{thJC}	-	-	3.3	°C/W
Thermal resistance, junction-ambient	$R_{thJA}^{②}$	-	-	40	°C/W
Soldering temperature	Tsold	-	-	260	°C

•Electronic Characteristics (Tj=25°C,unless otherwise specified)

Parameter	Symbol	Condition	Min.	Typ.	Max.	Unit
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0V, I_D=250\mu A$	1700	-	-	V
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{GS}=V_{DS}, I_D=1mA$	3	3.9	5	V
Drain-Source Leakage Current	I_{DSS}	$V_{GS}=0V, V_{DS}=1700V$	-	-	10	μA
Gate- Source Leakage Current	I_{GSS}	$V_{GS}=-10V, V_{DS}=0V$	-	-	-100	nA
	I_{GSS}	$V_{GS}=25V, V_{DS}=0V$	-	-	100	nA
Static Drain-source On Resistance	$R_{DS(ON)}$	$V_{GS}=18V, I_D=2A, T_j=25^\circ C$	-	750	900	m Ω
		$V_{GS}=18V, I_D=2A, T_j=175^\circ C$	-	1327	-	m Ω
		$V_{GS}=15V, I_D=2A, T_j=25^\circ C$	-	980	-	m Ω
Forward Transconductance	g_{FS}	$V_{DS}=20V, I_{SD}=2A$	-	1.2	-	S
Diode Forward Voltage	V_{FSD}	$V_{GS}=-4V, I_{SD}=2A$	-	3.9	5	V

•Dynamic characteristics (Tj=25°C,unless otherwise specified)

Parameter	Symbol	Condition	Min.	Typ.	Max.	Unit
Input capacitance	C_{iss}	$f=100KHz, V_{DS}=1000V, V_{GS}=0V$	-	167	-	pF
Output capacitance	C_{oss}		-	12.6	-	
Reverse transfer capacitance	C_{rss}		-	1.5	-	
Output Charge	Q_{oss}	$f=100KHz, V_{GS}=0V, V_{DS}=0V \text{ to } 1000V$	-	20.4	-	nC
Coss Stored Energy	E_{oss}		-	7.4	-	μJ
Gate Resistance	R_g	$f=1MHz$	-	23	-	Ω
Total gate charge	Q_g	$V_{DD}=1200V, I_D=2A, V_{GS}=-4V/18V$	-	14.5	-	nC
Gate - Source charge	Q_{gs}		-	2.7	-	
Gate - Drain charge	Q_{gd}		-	9.0	-	
Turn-ON Delay time	$t_{D(on)}$	$V_{GS}=-4V/18V, V_{DS}=1200V, R_G=10\Omega, I_D=2A$	-	5	-	ns
Turn-ON Rise time	t_r		-	18	-	ns
Turn-Off Delay time	$t_{D(off)}$		-	13	-	ns
Turn-Off Fall time	t_f		-	59	-	ns
Turn-On Energy	E_{on}		-	83	-	μJ
Turn-Off Energy	E_{off}		-	13	-	μJ
Reverse Recovery Time	t_{rr}	$V_{DD}=1200V, dI_S/dt=1000A/\mu s, I_S=2A$	-	28	-	ns
Reverse Recovery Charge	Q_{rr}		-	29	-	nC

Fig.1 Gate-source voltage as a function of gate charge; Typical values; $T_j=25^\circ\text{C}$

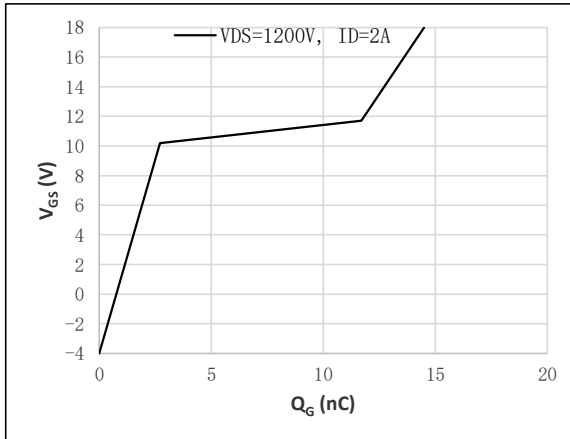


Fig.2 Input, output and reverse transfer capacitances as a function of drain-source voltage; Typical values; $T_j=25^\circ\text{C}$

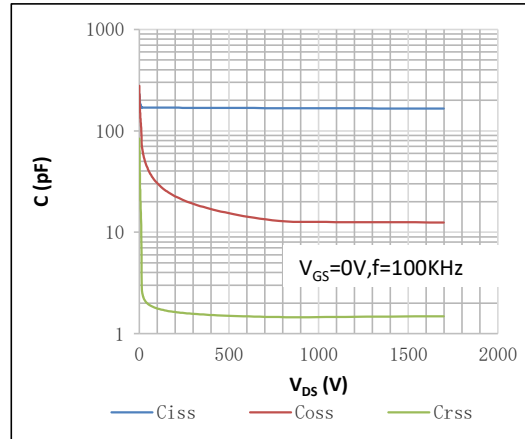


Fig.3 Output characteristics: drain current as a function of drain-source voltage; Typical values; $T_j=25^\circ\text{C}$

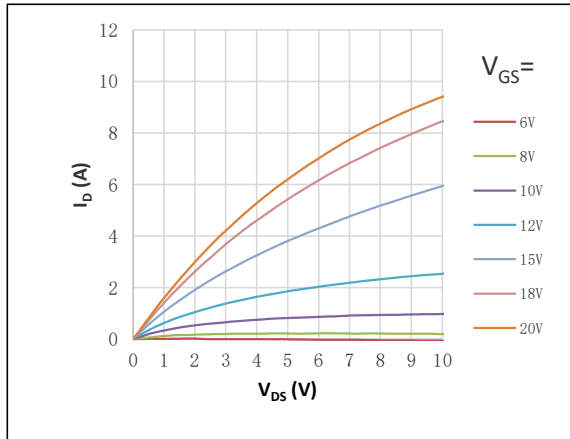


Fig.4 Output characteristics: drain current as a function of drain-source voltage; Typical values: Expanded curve; $T_j=25^\circ\text{C}$

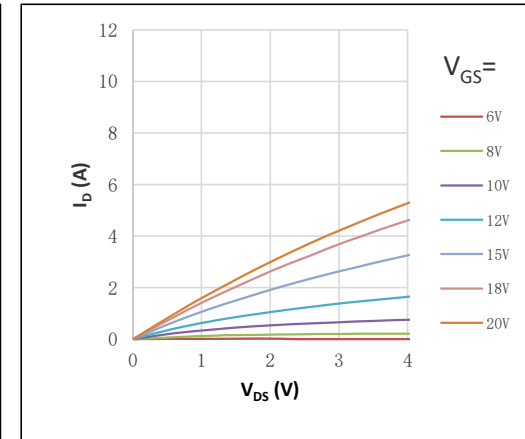


Fig.5 Gate-source threshold voltage as a function of junction temperature; Typical values

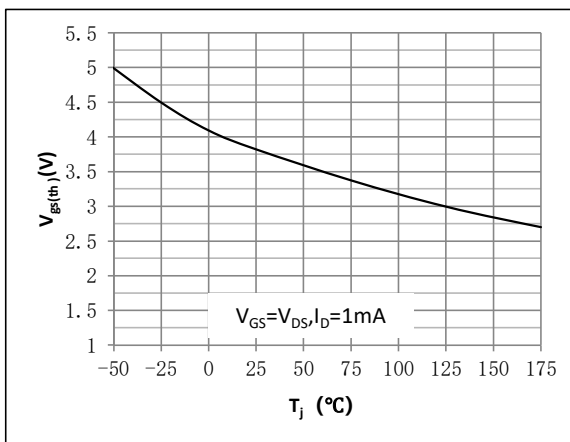


Fig.6 Drain-source on-state resistance as a function of drain current; Typical values; $T_j=25^\circ\text{C}$

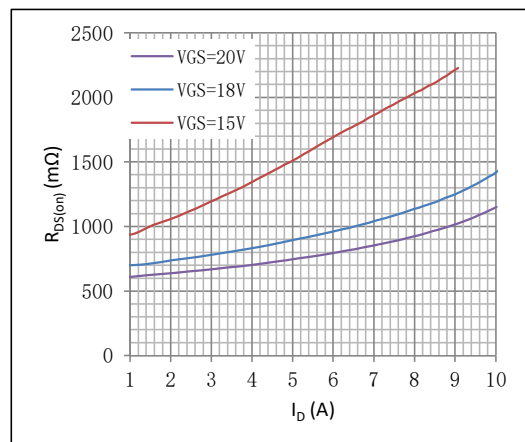


Fig.7 Drain-source on-state resistance as a function of gate-source voltage;Typical values

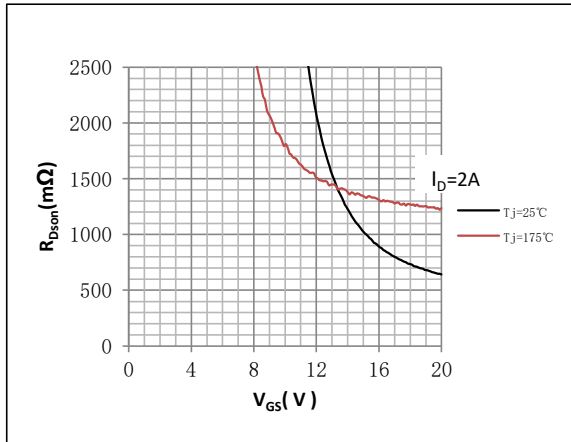


Figure 9. Source (diode forward) current as a function of source-drain (diode forward) voltage ;Typical values

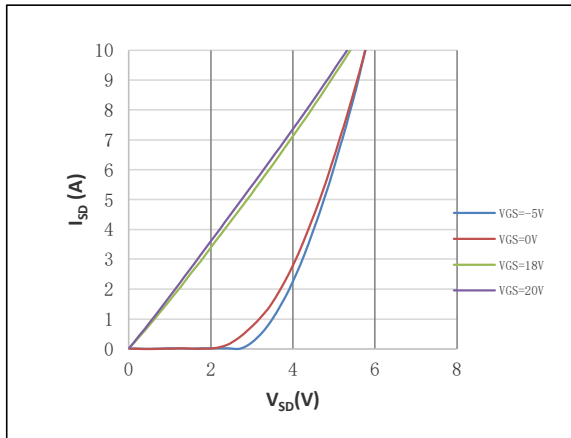


Fig.11 Safe operating area: continuous and peak drain currents as a function of drain-source voltage;Calculative values

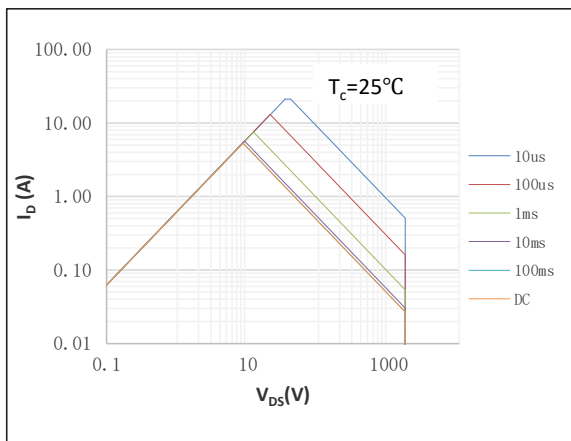


Fig.8 Normalized drain-source on-state resistance factor as a function of junction temperature;Typical values
Normalized On-Resistance= $R_{DS(on)}/R_{DS(on)}(25^{\circ}\text{C})$

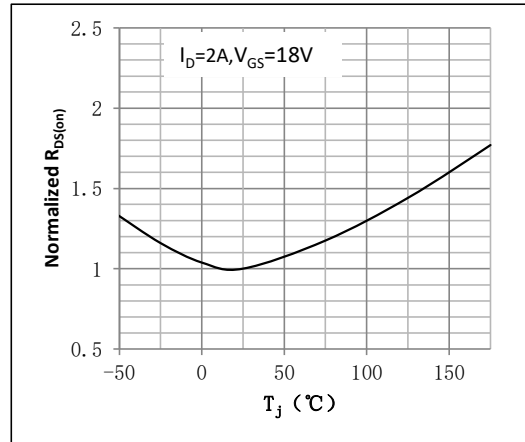


Figure 10. Transfer characteristics: drain current as a function of gate-source voltage;Typical values

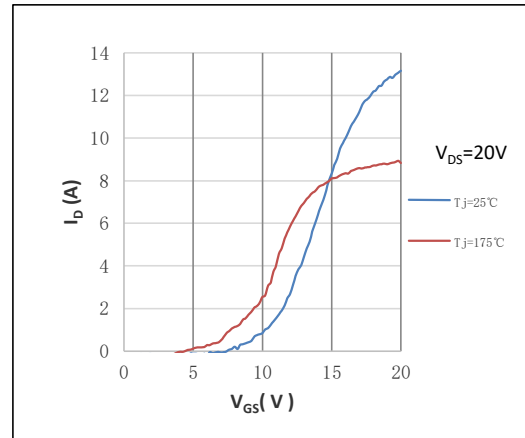


Fig.12 Continuous drain current as a function of case temperature^Θ;Calculative values

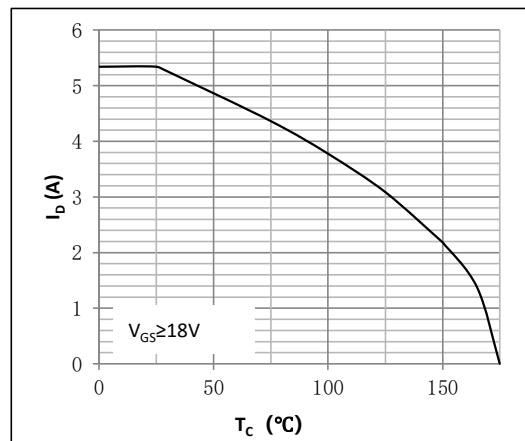


Fig.13 Drain-source breakdown voltage as a function of junction temperature; Typical values
Normalized BVDSS=BVDSS/BVDSS(25°C)

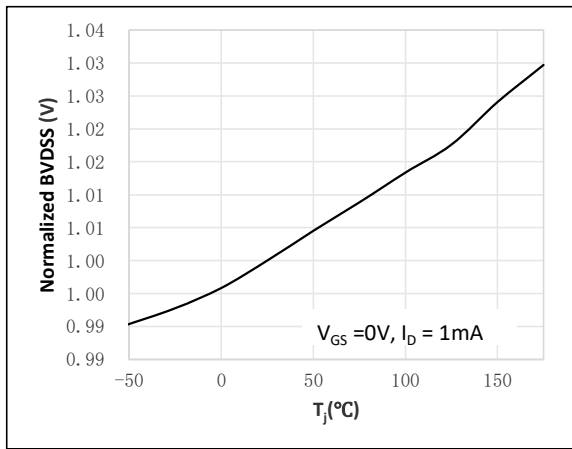


Fig.14 Normalized total power dissipation as a function of case temperature; Calculative values
Normalized Power Dissipation= $P_d/P_d(25^\circ C)$

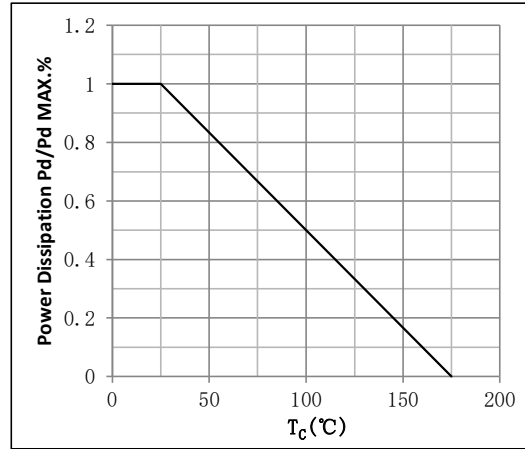


Fig.15 Transient thermal impedance from junction to case as a function of pulse duration; max values

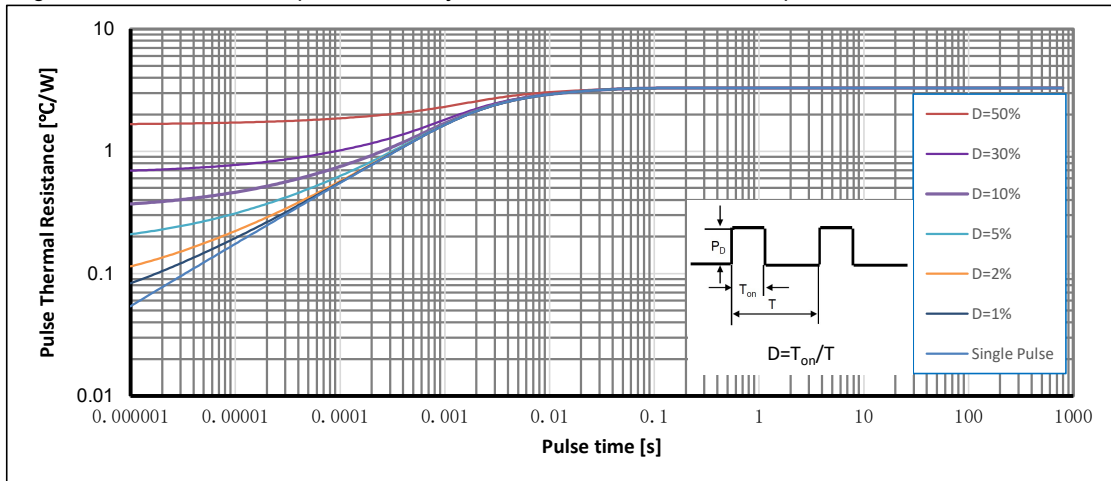
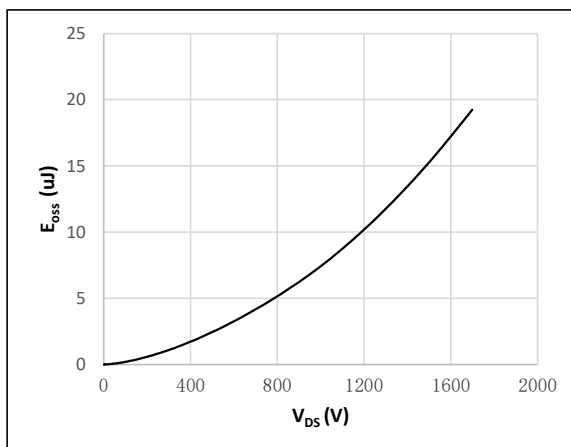
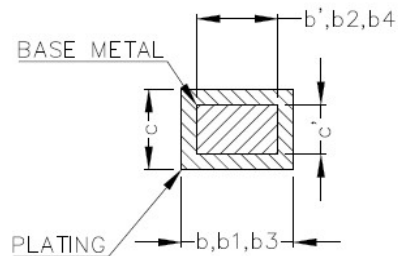
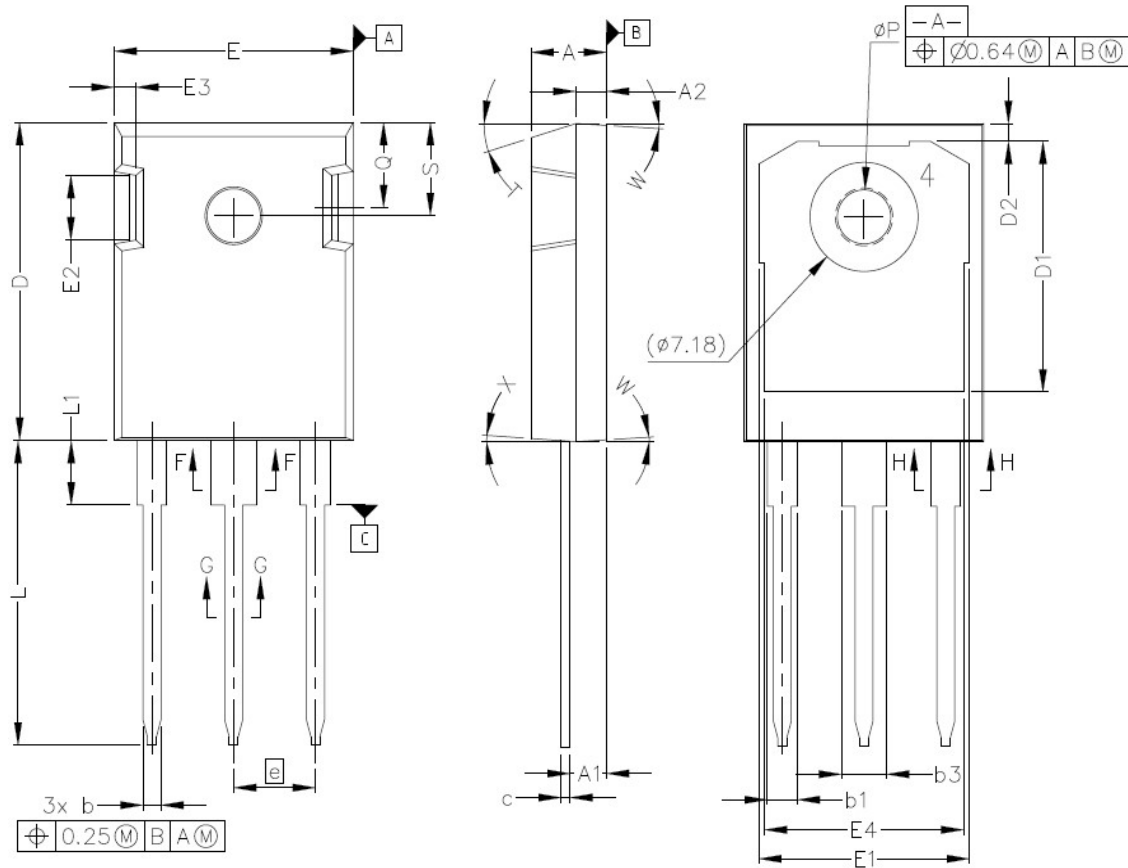


Fig.16 Output capacitor stored energy as a function of drain-source voltage; Typical values;
 $T_j=25^\circ C$



•TO-247-3 Package Outline



SECTION "F-F", "G-G" AND "H-H"
SCALE: NONE

Note:

- ① The value of R θ JA is measured with the device in a still environment with TA=25°C
- ② Practically the current will be limited by PCB, thermal design and operating temperature. VGS=18V.

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Version	Date	Change
A	2025/5/27	New